

20V N+N-Channel Enhancement Mode MOSFET

Description

The AP9926A uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

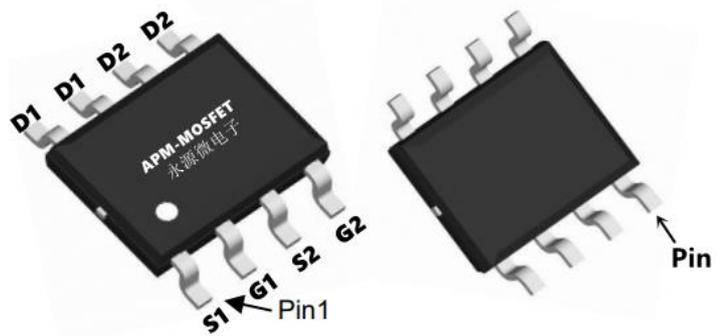
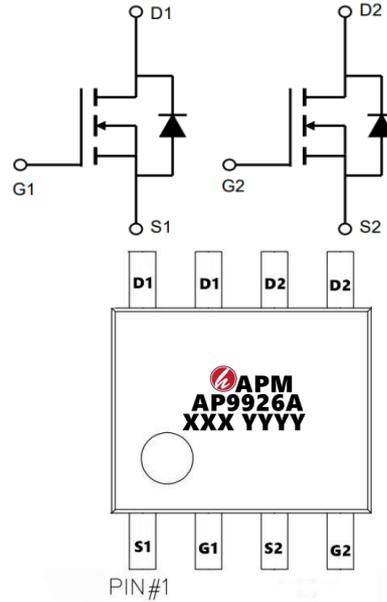
General Features

$V_{DS} = 20V$ $I_D = 8.2A$

$R_{DS(ON)} < 23m\Omega$ @ $V_{GS}=4.5V$ (Type: 17m Ω)

Application

- Battery protection
- Load switch
- Uninterruptible power supply



Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|--------|------------------|----------|
| AP9926A | SOP-8L | AP9926A XXX YYYY | 3000 |

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

| Symbol | Parameter | Rating | Units |
|------------------------|--|------------|--------------|
| V_{DS} | Drain-Source Voltage | 20 | V |
| V_{GS} | Gate-Source Voltage | ± 12 | V |
| $I_D @ T_A=25^\circ C$ | Continuous Drain Current, $V_{GS} @ 4.5V^1$ | 8.2 | A |
| $I_D @ T_A=70^\circ C$ | Continuous Drain Current, $V_{GS} @ 4.5V^1$ | 5.8 | A |
| I_{DM} | Pulsed Drain Current ² | 30.6 | A |
| $P_D @ T_A=25^\circ C$ | Total Power Dissipation ³ | 1.25 | W |
| T_{STG} | Storage Temperature Range | -55 to 150 | $^\circ C$ |
| T_J | Operating Junction Temperature Range | -55 to 150 | $^\circ C$ |
| $R_{\theta JA}$ | Thermal Resistance Junction-ambient ¹ | 85 | $^\circ C/W$ |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case ¹ | 74 | $^\circ C/W$ |

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Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

| Symbol | Parameter | Test Condition | Min. | Typ. | Max. | Units |
|----------|--|--|------|------|-----------|------------|
| V(BR)DSS | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_D=250\mu A$ | 20 | 22 | - | V |
| IDSS | Zero Gate Voltage Drain Current | $V_{DS}=20V, V_{GS}=0V,$ | - | - | 1.0 | μA |
| IGSS | Gate to Body Leakage Current | $V_{DS}=0V, V_{GS}=\pm 12V$ | - | - | ± 100 | nA |
| VGS(th) | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=250\mu A$ | 0.4 | 0.7 | 1.0 | V |
| RDS(on) | Static Drain-Source on-Resistance note2 | $V_{GS}=4.5V, I_D=4.5A$ | - | 17 | 23 | m Ω |
| | | $V_{GS}=2.5V, I_D=2.5A$ | - | 21 | 28 | |
| Ciss | Input Capacitance | $V_{DS}=10V, V_{GS}=0V,$ $f=1.0MHz$ | - | 358 | - | pF |
| Coss | Output Capacitance | | - | 69.3 | - | pF |
| Crss | Reverse Transfer Capacitance | | - | 58.5 | - | pF |
| Qg | Total Gate Charge | $V_{DS}=10V, I_D=3A,$ $V_{GS}=4.5V$ | - | 5.6 | - | nC |
| Qgs | Gate-Source Charge | | - | 0.8 | - | nC |
| Qgd | Gate-Drain("Miller") Charge | | - | 1 | - | nC |
| td(on) | Turn-on Delay Time | $V_{DS}=10V,$ $I_D=6A, R_{GEN}=3\Omega,$ $V_{GS}=4.5V$ | - | 16 | - | ns |
| tr | Turn-on Rise Time | | - | 51 | - | ns |
| td(off) | Turn-off Delay Time | | - | 21 | - | ns |
| tf | Turn-off Fall Time | | - | 19 | - | ns |
| IS | Maximum Continuous Drain to Source Diode Forward Current | | - | - | 6 | A |
| ISM | Maximum Pulsed Drain to Source Diode Forward Current | | - | - | 24 | A |
| VSD | Drain to Source Diode Forward Voltage | $V_{GS}=0V, I_S=6A$ | - | - | 1.2 | V |

Note :

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3、 The power dissipation is limited by 150 $^{\circ}\text{C}$ junction temperature
- 4、 The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

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Typical Characteristics

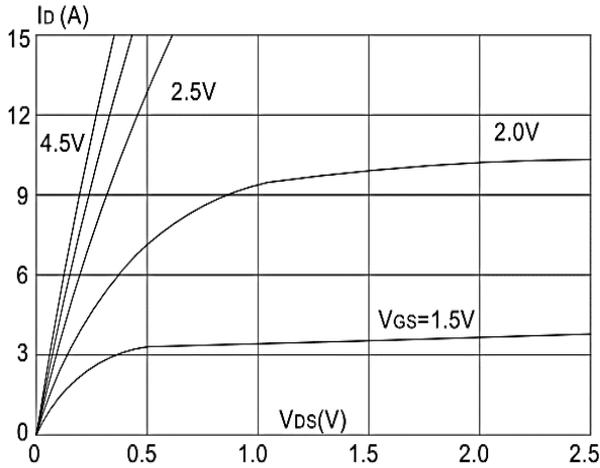


Figure 1: Output Characteristics

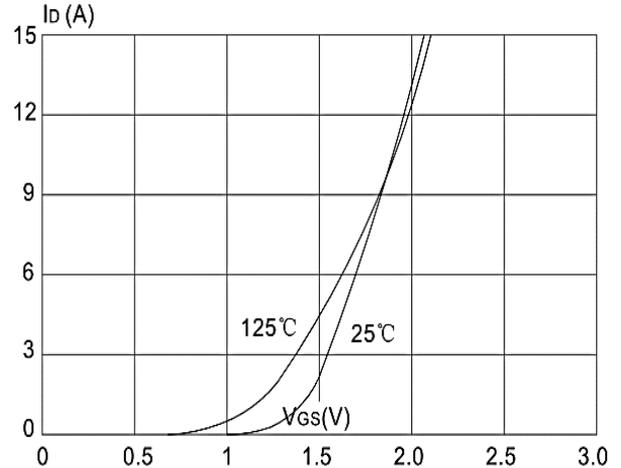


Figure 2: Typical Transfer Characteristics

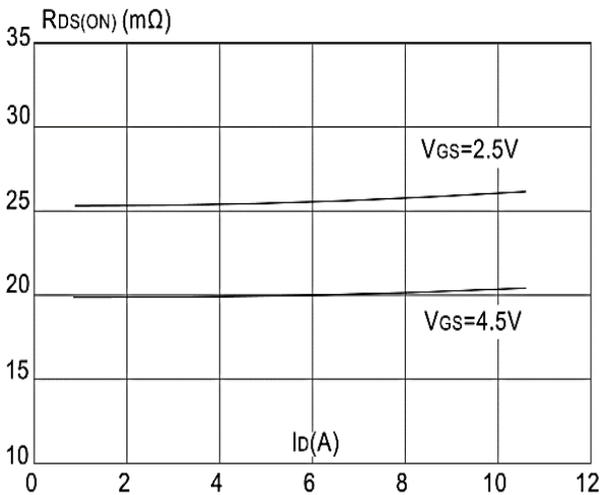


Figure 3: On-resistance vs. Drain Current

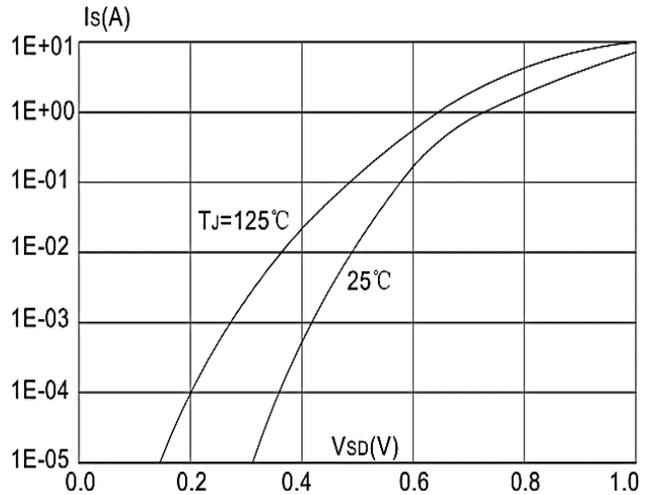


Figure 4: Body Diode Characteristics

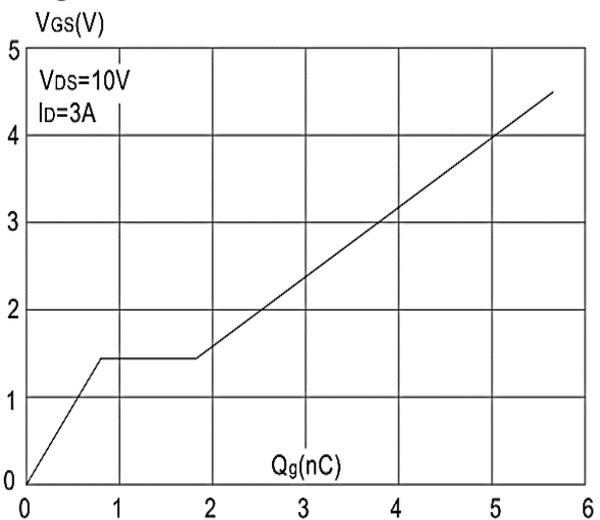


Figure 5: Gate Charge Characteristics

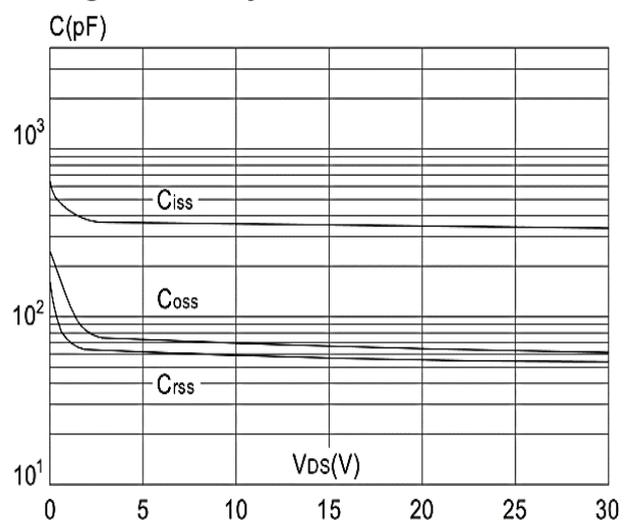


Figure 6: Capacitance Characteristics



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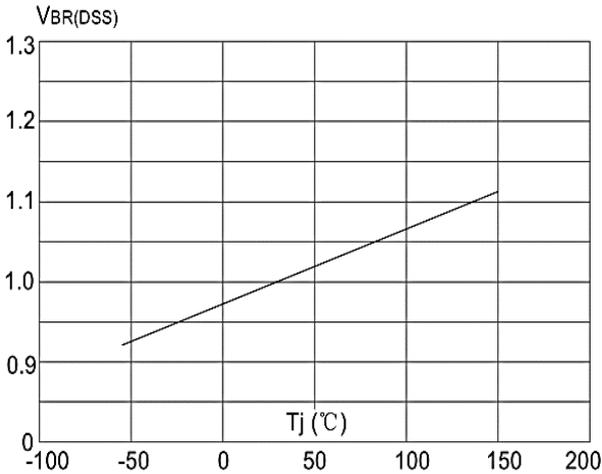


Figure 7: Normalized Breakdown Voltage vs Junction Temperature

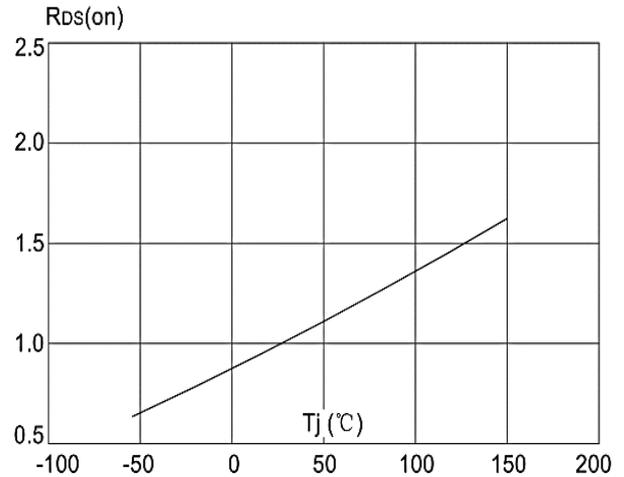


Figure 8: Normalized on Resistance vs. Junction Temperature

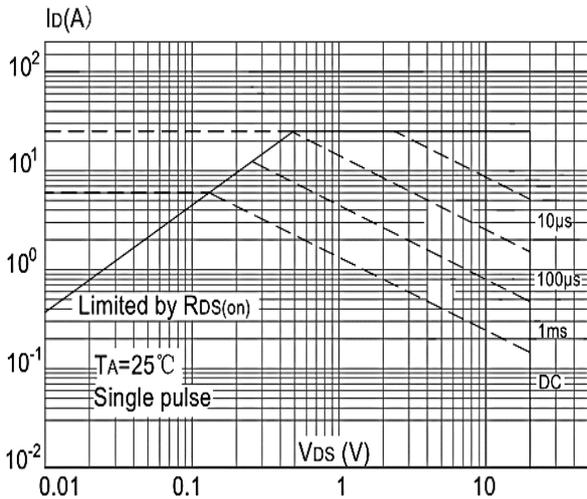


Figure 9: Maximum Safe Operating Area

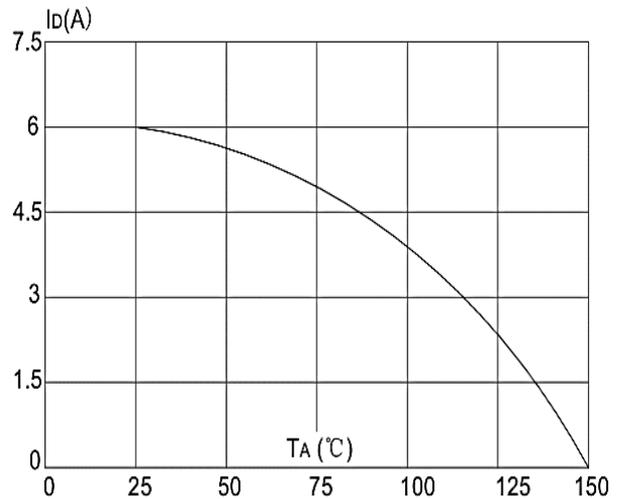


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

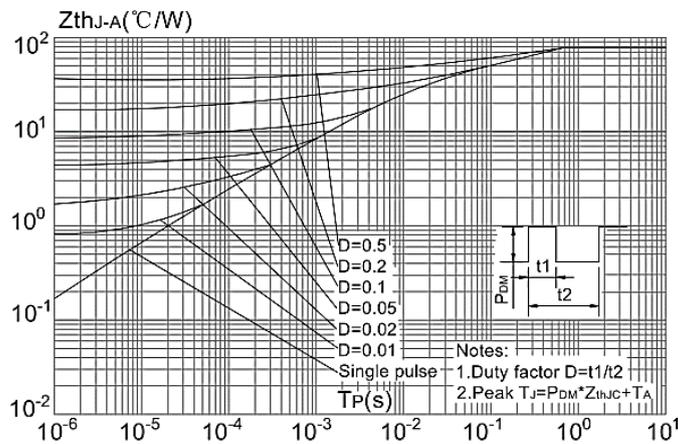
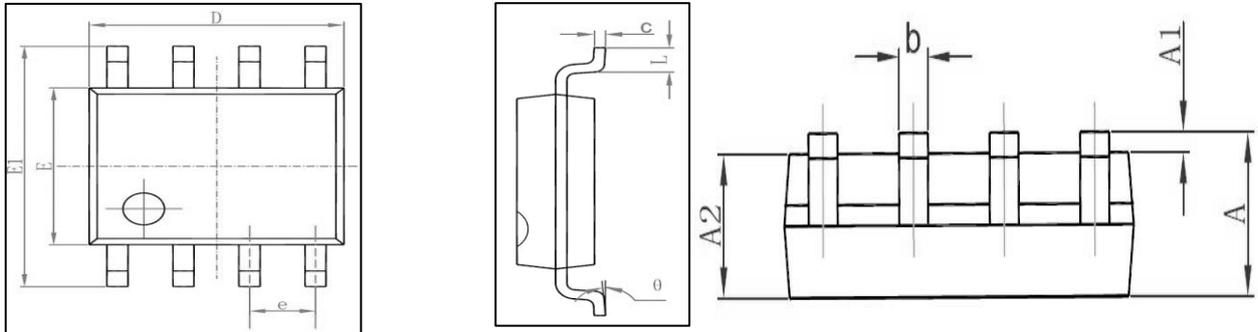


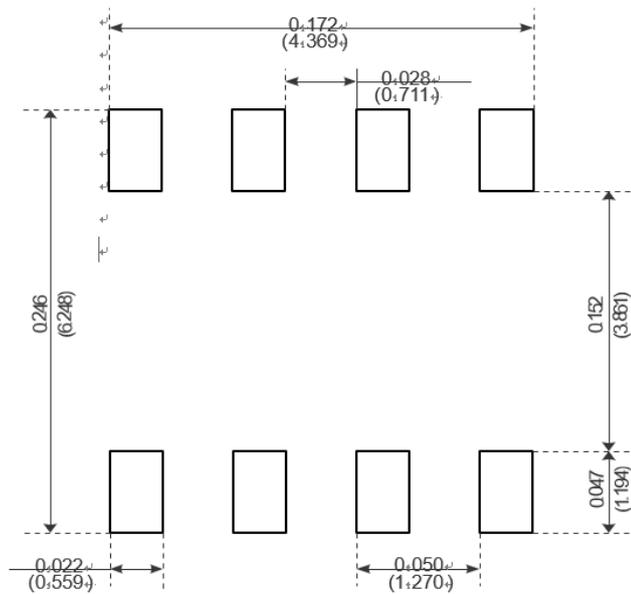
Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien

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Package Mechanical Data-SOP-8L



| Symbol | Dimensions In Millimeters | | Dimensions In Inches | |
|--------|---------------------------|-------|----------------------|-------|
| | Min | Max | Min | Max |
| A | 1.350 | 1.750 | 0.053 | 0.069 |
| A1 | 0.100 | 0.250 | 0.004 | 0.010 |
| A2 | 1.350 | 1.550 | 0.053 | 0.061 |
| b | 0.330 | 0.510 | 0.013 | 0.020 |
| c | 0.170 | 0.250 | 0.006 | 0.010 |
| D | 4.700 | 5.100 | 0.185 | 0.200 |
| E | 3.800 | 4.000 | 0.150 | 0.157 |
| E1 | 5.800 | 6.200 | 0.228 | 0.244 |
| e | 1.270 (BSC) | | 0.050 (BSC) | |
| L | 0.400 | 1.270 | 0.016 | 0.050 |
| θ | 0° | 8° | 0° | 8° |



Recommended Minimum Pads

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| Edition | Date | Change |
|----------------|-------------|--------------------------------|
| RVE3.3 | 2018/12/1 | Initial release |
| RVE3.4 | 2021/3/31 | Change of specification format |
| RVE3.5 | 2023/2/06 | Reduce RDS (on) |

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